Just Enough Database for Manufacturing Yield Analysis

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The Completed paper was not available at press time.

Linda H. Tai will be presenting the paper and plans to have handouts of the paper available at the presentation.

Abstract

The IBM Storage Systems Division operates advanced manufacturing facilities for fabricating, assembling and testing all of the major components of IBM data storage products. The operational data from our manufacturing sites are also used for engineering analysis, yield management and problem diagnosis. This cross-functional data allows us to exploit the benefit of vertical integration by analyzing the relationships between hard drive performance and component measurements, and using the resulting insight to eliminate yield detractors and optimize specifications. The Just Enough Database project was undertaken to optimize our use of operational data for yield analysis. The JED system consists of a Data Warehouse, which combines and correlates data from several operational databases, and a graphical user interface, which automates the yield analysis process. The user interface was written in SAS/AF, to run on the SAS system for PCs. It has since been ported to run on a web browser using SAS/INTERNET.